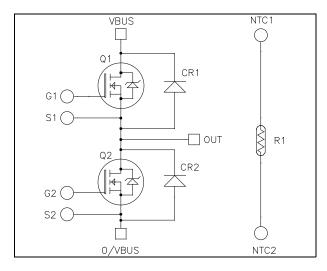


Phase leg SiC MOSFET Power Module

$$\begin{split} V_{DSS} &= 1200 V \\ R_{DSon} &= 8 m \Omega \ typ \ @ \ Tj = 25^{\circ} C \\ I_D &= 370 A \ @ \ Tc = 25^{\circ} C \end{split}$$



Application

- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

Features

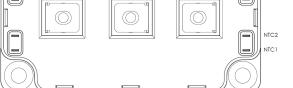
- SiC Power MOSFET
 - Low $R_{DS(on)}$
 - High temperature performance

• SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin source for easy drive
- Very low stray inductance
- M5 power connectors
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance

Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Low profile
- RoHS Compliant



O/VBUS

All ratings @ $T_j = 25$ °C unless otherwise specified

Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1200	V
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	370	
I_D	Continuous Drain Current	$T_c = 80$ °C	290	A
I_{DM}	Pulsed Drain current	•		
V_{GS}	Gate - Source Voltage		-10/+25	V
R_{DSon}	Drain - Source ON Resistance		10	$m\Omega$
P_{D}	Power Dissipation	$T_c = 25^{\circ}C$	2300	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



Electrical Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$; $V_{DS} = 1200V$			100	1000	μA
D	Drain – Source on Resistance	$V_{GS} = 20V$	$T_i = 25^{\circ}C$		8	10	
R _{DS(on)}		$I_{\rm D} = 200 A$	$T_j = 175$ °C		14		mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 10 \text{mA}$		1.7	3		V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				1	μA

Dynamic Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V$			25		
C_{oss}	Output Capacitance	$V_{\rm DS} = 1000 V$			1.2		nF
C_{rss}	Reverse Transfer Capacitance	f = 1MHz			0.2		
Q_{g}	Total gate Charge	$ \begin{array}{c} - V_{GS} = -5/20V \\ V_{Bus} = 600V \\ I_D = 200A \end{array} $			1360		nC
Q_{gs}	Gate – Source Charge				400		
Q_{gd}	Gate – Drain Charge				400		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching $V_{GS} = -5/20V ; V_{Bus} = 800V$ $I_D = 200A ; T_J = 150^{\circ}C$			10		
T_{r}	Rise Time				10		ns
$T_{d(off)}$	Turn-off Delay Time				45		
T_{f}	Fall Time	$R_G = 0.5\Omega$			30		
E _{on}	Turn on Energy	$V_{\text{Bus}} = 600 \text{V}$ $I_{\text{B}} = 200 \text{A}$	$T_j = 150$ °C		4.3		mJ
$E_{ m off}$	Turn off Energy		$T_j = 150^{\circ}C$		2.4		mJ
R_{Gint}	Internal gate resistance				0.33		Ω
R_{thJC}	Junction to Case Thermal Resistance	e				0.065	°C/W

Body diode ratings and characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
V_{SD}	Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 200A$		3.9		V
t_{rr}	Reverse Recovery Time	$I_{SD} = 200 A \; ; \; V_{GS} = -2 V \\ V_R = 800 V \; ; \; di_F/dt = 1000 A/\mu s \; - 1000 A/\mu s \; -$		140		ns
Q_{rr}	Reverse Recovery Charge			1150		nC
I_{rr}	Reverse Recovery Current			20		Α



SiC diode ratings and characteristics (Per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Peak Repetitive Reverse Voltage					1200	V
T	December Leader of Comment	V _R =1200V	$T_j = 25$ °C		0.1	2	mΛ
I_{RM}	Reverse Leakage Current		$T_j = 175$ °C		5		mA
I_F	DC Forward Current		Tc = 125°C		100		Α
V	Diada Farward Valtaga	$I_{F} = 100A$	$T_j = 25^{\circ}C$		1.5	1.8	V
V_{F}	Diode Forward Voltage		$T_i = 175$ °C		2.3		V
$Q_{\rm C}$	Total Capacitive Charge	$I_F = 100A ; V_R = 600V$ $di/dt = 5000A/\mu s$			1200		nC
С	Total Capacitance	$f = 1MHz, V_R = 200V$	= 200V		1150		ъE
		$f = 1 MHz, V_R$	= 400V		850		pF
R_{thJC}	Junction to Case Thermal Resistance				0.11	°C/W	

Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit			
V_{ISOL}	RMS Isolation Voltage, any terminal to case t = 1 min, 50/60Hz			4000		V			
T_{J}	Operating junction temperature range			-40	175				
T_{JOP}	Recommended junction temperature un	ditions	-40	T _J max -25	°C				
T_{STG}	Storage Temperature Range		-40	125	C				
$T_{\rm C}$	Operating Case Temperature				125				
Torque	Mounting torque	To heatsink	M6	3	5	N.m			
Torque	Woulding torque	For terminals	M5	2	3.5	18.111			
Wt	Package Weight				300	g			

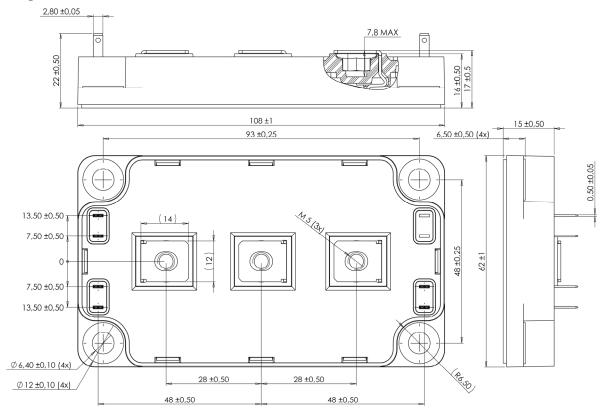
Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic	,	Min	Тур	Max	Unit
R ₂₅	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
$B_{25/85}$	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp \left[B_{25/85} \left(\frac{1}{T_{75}} - \frac{1}{T} \right) \right]}$$
 T: Thermistor temperature R_T: Thermistor value at T



Package outline (dimensions in mm)

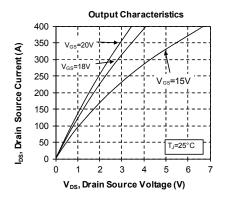


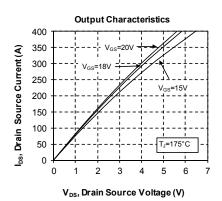
See application note APT0601 - Mounting Instructions for SP6 Power Modules on www.microsemi.com

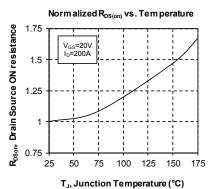
4-8

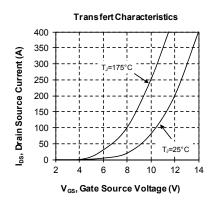


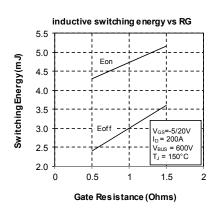
Typical SiC MOSFET Performance Curve

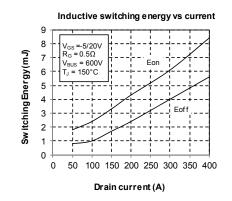


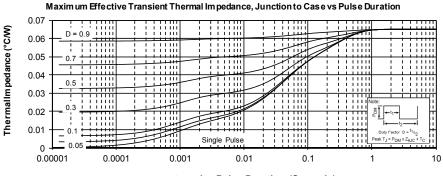






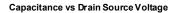


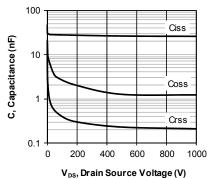




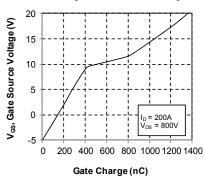
rectangular Pulse Duration (Seconds)



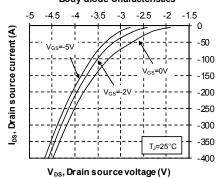




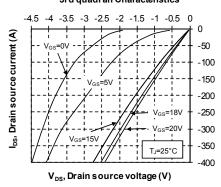
Gate Charge vs Gate Source Voltage

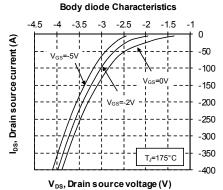


Body diode Characteristics

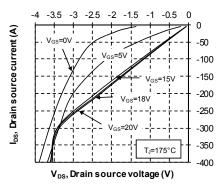


3rd quadran Characteristics

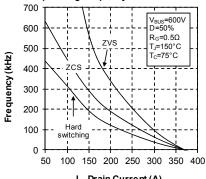




3rd quadran Characteristics



Operating Frequency vs Drain Current

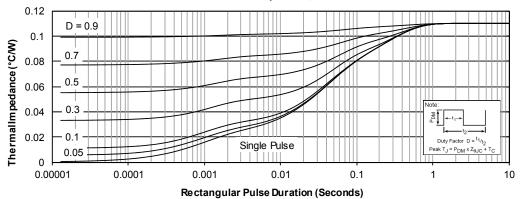


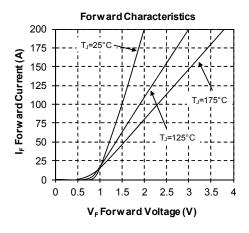
I_D, Drain Current (A)

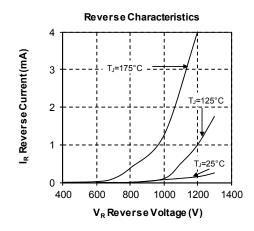


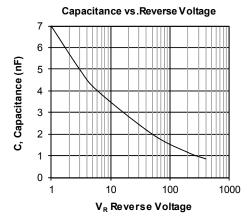
Typical SiC diode Performance Curve

Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration









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